

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1839	SERIAL NO. <i>10/09/03</i>
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Farnworth et al.	
				FILING DATE	GROUP <i>3729</i>

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>WAT</i>	AA	6,063,701	05/16/00	Kuwazaki et al.	—	—	
	AB	5,899,737	05/04/99	Trabucco	—	—	
	AC	5,763,854	06/09/98	Dittman et al.	—	—	
	AD	5,762,258	06/09/98	Le Coz et al.	—	—	
	AE	5,495,089	02/27/96	Freedman et al.	—	—	
	AF	5,431,332	07/11/95	Kirby et al.	—	—	
	AG	6,162,661	12/19/00	Link	—	—	
	AH	6,056,190	05/02/00	Foulke et al.	—	—	
	AI	5,839,641	11/24/98	Teng	—	—	
	AJ	5,655,704	08/12/97	Sakemi et al.	—	—	
<i>WAT</i>	AK	5,620,927	04/15/97	Lee	—	—	

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
<i>WAT</i> AL	WO 99/17593	04/08/99	PCT	—	—		
AM	8-118005 A	05/14/96	Japan	—	—		
<i>WAT</i> AN	NL 1007949	01/05/98	Netherlands	—	—		
AO							
AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
<i>WAT</i>	AR	Kasulke et al., <i>Solder Ball Bumper (SBB) - A Flexible Equipment for FC, CSP, BGA and Printed Circuit Boards/An Innovative Solution for,</i>	
		<i>Solder Application Solder Ball Bumper (SBB)</i> , Pac Tech Packaging Technologies GmbH and Fraunhofer IZM, pp. 1-8.	
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EXAMINER <i>[Signature]</i>	DATE CONSIDERED <i>5/30/03</i>
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1839		SERIAL NO. <i>19 004,172</i>		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnworth et al.		GROUP <i>3729</i>		
				FILING DATE				
U.S. PATENT DOCUMENTS								
*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>INT</i>	AA	5,219,117	06/15/93	Lin	—	—		
	AB	4,871,110	10/03/89	Fukasawa et al.	—	—		
	AC	6,234,382 B1	05/22/01	Rischke et al.	—	—		
	AD	5,750,199	05/12/98	Sakemi	—	—		
	AE	5,164,566	11/17/92	Spletter et al.	—	—		
	AF	4,661,192	04/28/87	McShane	—	—		
	AG	4,831,724	05/23/89	Elliott	—	—		
	AH	5,052,102	10/01/91	Fong et al.	—	—		
	AI	5,479,703	01/02/96	Desai et al.	—	—		
	AJ	5,551,148	09/03/96	Kazui et al.	—	—		
<i>INT</i>	AK	5,654,204	08/05/97	Anderson	—	—		
	FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation	
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				FILING DATE				
U.S. PATENT DOCUMENTS								
*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>WMT</i>	AA	5,941,449	08/24/99	Le Coz et al.	—	—		
	AB	5,782,399	07/21/98	Lapastora	—	—		
	AC	5,745,986	05/05/98	Variot et al.	—	—		
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FOREIGN PATENT DOCUMENTS								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR		<div style="position: relative; height: 150px;"> <div style="position: absolute; top: 0; left: 0; right: 0; bottom: 0; border-left: 2px solid black; border-right: 2px solid black;"></div> </div>					
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EXAMINER <i>[Signature]</i>			DATE CONSIDERED <i>5/30/03</i>					
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<div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block; text-align: center;"> OIP APR 10 2003 PATENT & TRADEMARK OFFICE </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
APPLICANT Warren M. Farnworth et al.				FILING DATE October 9, 2001		GROUP 3729	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
AA							
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						Yes	No
AJ							
AK							
AL							
AM							
AN							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
AO		Yariv, Amnon, "Quantum Electronics - Second Edition," ©1967, 1975, by John Wiley & Sons, Inc., pages 176-193.					
AP		Yariv, Amnon, "Quantum Electronics - Second Edition," ©1967, 1975, by John Wiley & Sons, Inc., pages 300-307.					
AQ		Eisberg et al., "Quantum Physics of Atoms, Molecules, Solids, Nuclei, and Particles," ©1974 by John Wiley & Sons, Inc., page 316.					
AR		Eisberg et al., "Quantum Physics of Atoms, Molecules, Solids, Nuclei, and Particles," ©1974 by John Wiley & Sons, Inc., pages 425-433.					
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				5/30/93			
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WMT	AA	6,412,683 B2	7/2/2002	Hertz et al.	—	—	
WMT	AB	2002/0045521 A1	4/11/2002	Farnworth et al.	—	—	
	AC						
	AD						
	AE						
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AG						
	AH						
	AI						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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Warren M. Farnworth et al.FILING DATE
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WMT	AA	5,977,512	11/02/99	Azdasht et al.	—	—	
	AB	5,741,410	04/21/98	Tsurushima	—	—	
	AC	5,279,045	01/18/94	Odashima et al.	—	—	
WMT	AD	5,159,171	10/27/92	Cook et al.	—	—	
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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
WMT	AN	EP 0 964 608 A2	12/15/99	EPO	—	—		
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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